# MOSFET – Power, Single, N-Channel, SO-8 FL 30 V, 147 A

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### **Applications**

• CPU Power Delivery, DC-DC Converters

# **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

	` `			<u> </u>	
Parai	meter		Symbol	Value	Unit
Drain-to-Source Volta	ge		$V_{DSS}$	30	V
Gate-to-Source Voltag	je		$V_{GS}$	±20	V
Continuous Drain		T <sub>A</sub> = 25°C	Ι <sub>D</sub>	29.1	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 100°C		18.4	
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.72	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	47.5	Α
Current R <sub>θJA</sub> ≤ 10 s (Note 1)		T <sub>A</sub> = 100°C		30.0	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	7.23	W
Continuous Drain	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	17.1	Α
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 100°C		10.8	
Power Dissipation $R_{\theta JA}$ (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.93	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	147	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> =100°C		93	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	69.44	W
Pulsed Drain Current	$T_A = 25^{\circ}$	°C, t <sub>p</sub> = 10 μs	$I_{DM}$	442	Α
Current Limited by Pac	kage	T <sub>A</sub> = 25°C	I <sub>Dmax</sub>	100	Α
Operating Junction and	d Storage∃	Temperature	T <sub>J</sub> , T <sub>STG</sub>	–55 to +150	°C
Source Current (Body I	Diode)		IS	68	Α
Drain to Source DV/DT			dV/d <sub>t</sub>	6	V/ns
Single Pulse Drain-to- Energy $T_J = 25^{\circ}C$ , $V_{DD}$ $I_L = 37 A_{pk}$ , $L = 0.3 mH$	$_{0} = 24 \text{ V}, \text{ V}_{0}$	<sub>GS</sub> = 10 V,	E <sub>AS</sub>	205	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

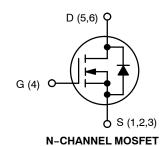
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



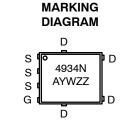
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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
30 V	2.0 mΩ @ 10 V	447.0	
	3.0 m $\Omega$ @ 4.5 V	147 A	







A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4934NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4934NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

1. 2.	Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu. Surface-mounted on FR4 board using the minimum recommended pad size.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	1.8	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	46.0	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	134.2	-C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 3)	$R_{\theta JA}$	17.3	

Parameter	Symbol	otherwise specified)  Test Condition		Min	Typ	Max	Unit
	Symbol			IVIIII	Тур	IVIAX	Unit
OFF CHARACTERISTICS				1	1	1	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				15.2		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$				1.0	μΑ
			T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	<sub>S</sub> = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.2	1.6	2.2	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				4.6		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		1.52	2.0	
			I <sub>D</sub> = 15 A		1.52		1
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		2.2	3.0	mΩ
			I <sub>D</sub> = 15 A		2.2		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 15 A			80		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE						
Input Capacitance	C <sub>ISS</sub>				5505		
Output Capacitance	Coss	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			2355		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				90		-
Total Gate Charge	Q <sub>G(TOT)</sub>				34		1
	` '						1
Threshold Gate Charge	$Q_{G(TH)}$				3.8		
Threshold Gate Charge Gate-to-Source Charge	` '	$V_{GS}$ = 4.5 V, $V_{DS}$ =	15 V; I <sub>D</sub> = 30 A		3.8 13.9		nC
	Q <sub>GS</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ =	15 V; I <sub>D</sub> = 30 A				nC
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = $ $V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$			13.9		nC nC
Gate-to-Source Charge Gate-to-Drain Charge	Q <sub>GS</sub>				13.9 8.1		
Gate-to-Source Charge Gate-to-Drain Charge Total Gate Charge	Q <sub>GS</sub> Q <sub>GD</sub> Q <sub>G(TOT)</sub>				13.9 8.1		
Gate-to-Source Charge Gate-to-Drain Charge Total Gate Charge SWITCHING CHARACTERISTICS (Note 6)	Q <sub>GS</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> =	15 V; I <sub>D</sub> = 30 A		13.9 8.1 76.5		nC
Gate-to-Source Charge Gate-to-Drain Charge Total Gate Charge SWITCHING CHARACTERISTICS (Note 6) Turn-On Delay Time	Q <sub>GS</sub> Q <sub>GD</sub> Q <sub>G(TOT)</sub>		15 V; I <sub>D</sub> = 30 A		13.9 8.1 76.5		

Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

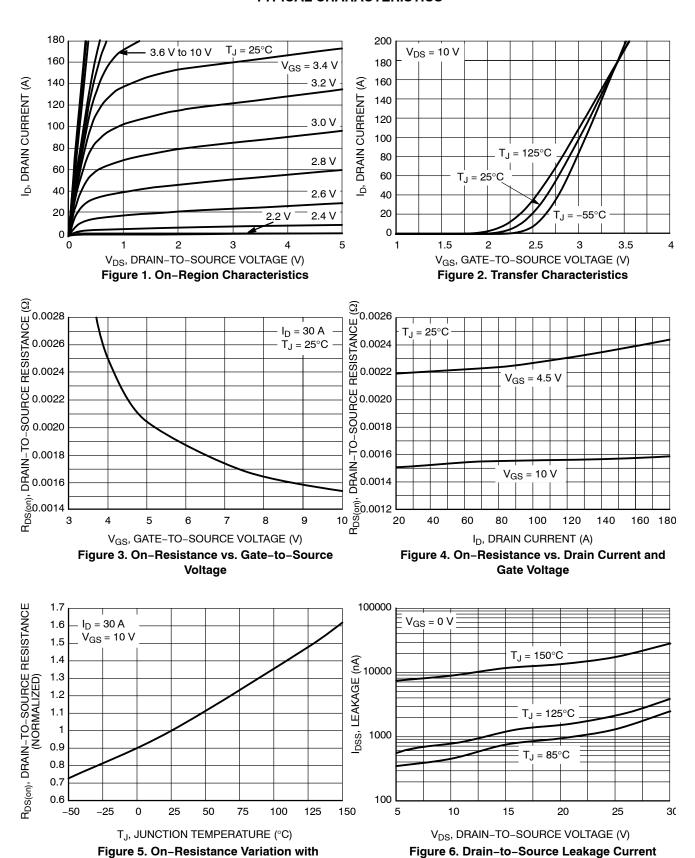
<sup>5.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
6. Switching characteristics are independent of operating junction temperatures.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 6)			•			
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$			13.2		
Rise Time	t <sub>r</sub>				33.3		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$R_G = 3.0$	Ω		49.7		ns
Fall Time	t <sub>f</sub>	1			7.8		
DRAIN-SOURCE DIODE CHARACTI	ERISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.79	1.0	.,,
		$V_{GS} = 0 \text{ V},$ $I_{S} = 30 \text{ A}$	T <sub>J</sub> = 125°C		0.66		V
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 30 A			59.1		ns
Charge Time	t <sub>a</sub>				28.3		
Discharge Time	t <sub>b</sub>	I <sub>S</sub> = 30	Α		30.8		
Reverse Recovery Charge	Q <sub>RR</sub>	1			70		nC
PACKAGE PARASITIC VALUES	-						
Source Inductance	L <sub>S</sub>				1.00		nΗ
Drain Inductance	L <sub>D</sub>	T <sub>A</sub> = 25°C			0.005		nΗ
Gate Inductance	L <sub>G</sub>				1.84		nΗ
Gate Resistance	R <sub>G</sub>				0.80		Ω

<sup>5.</sup> Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**



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vs. Voltage

**Temperature** 

#### **TYPICAL CHARACTERISTICS**

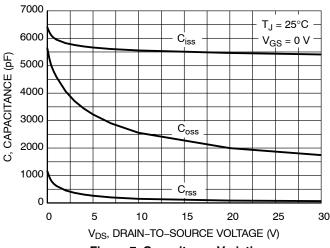


Figure 7. Capacitance Variation

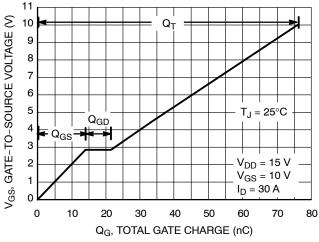


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

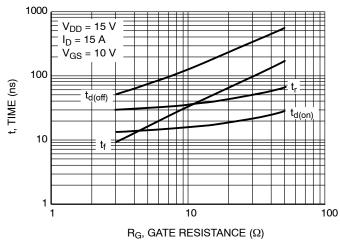


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

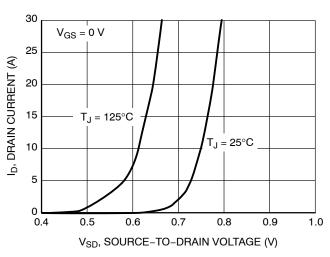


Figure 10. Diode Forward Voltage vs. Current

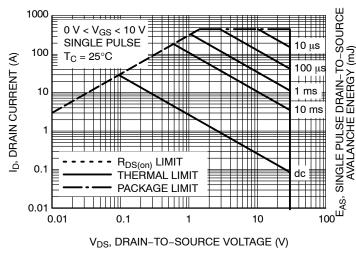


Figure 11. Maximum Rated Forward Biased Safe Operating Area

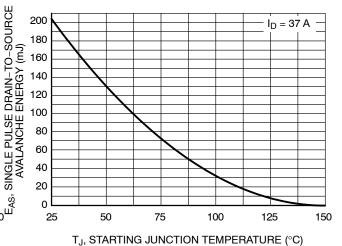


Figure 12. Maximum Avalanche Energy vs.

**Starting Junction Temperature** 

# **TYPICAL CHARACTERISTICS**

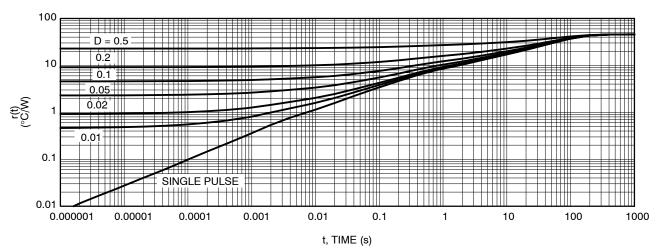


Figure 13. Thermal Response

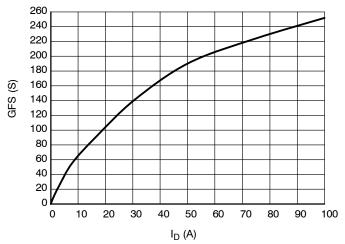
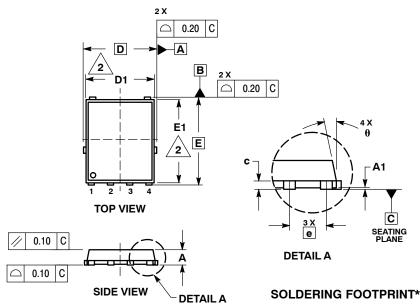


Figure 14. GFS vs. I<sub>D</sub>

#### PACKAGE DIMENSIONS



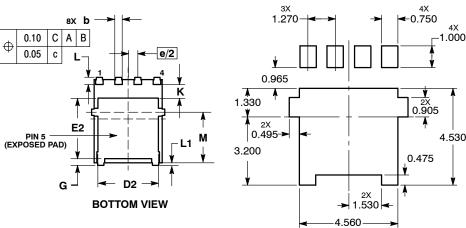


#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	0.90	1.00	1.10		
A1	0.00		0.05		
b	0.33	0.41	0.51		
С	0.23	0.28	0.33		
D	5.15 BSC				
D1	4.50	4.90	5.10		
D2	3.50		4.22		
Е	6.15 BSC				
E1	5.50	5.80	6.10		
E2	3.45		4.30		
е		1.27 BSC	;		
G	0.51	0.61	0.71		
K	1.20	1.35	1.50		
L	0.51	0.61	0.71		
L1	0.05	0.17	0.20		
М	3.00	3.40	3.80		
θ	0 °		12 °		

- STYLE 1: PIN 1. SOURCE
  - SOURCE
     SOURCE
  - GATE
  - 5. DRAIN



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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